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	Application/Control No.	Applicant(s)/Patent und Reexamination	er
	10/623,026	LEE ET AL.	
	Examiner	Art Unit	
_	Tuan V. Thai	2186	

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Class	Subclass	Date	Examiner
711	5	10/21/2005	тн
711	100	10/21/2005	тн
711	154	10/21/2005	ТН
711	170	10/21/2005	TH
711	200	10/21/2005	тн
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
IEEE search; NPL search; EAST searches: IBMTDB DERWENTS EPO/JPO abstract USPGPUB	1/31/2006	ТН
NORHT database		
		